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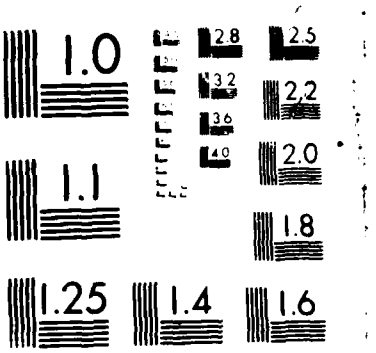
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by D. McCluskey

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CENTER FOR RELIABLE COMPUTING
Computer Systems Laboratory
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ABSTRACT

This report is a bibliography of the 1986 CRC Publications.

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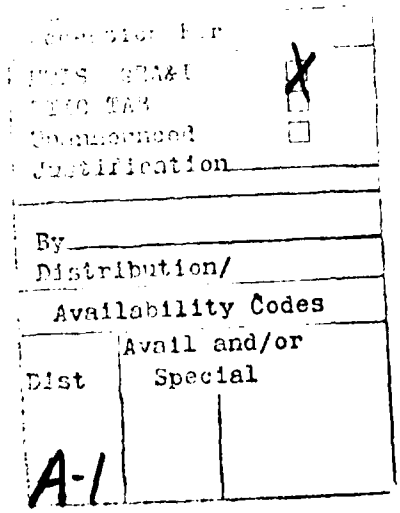

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LIST OF ABBREVIATIONS

ICCAD'86 = International Conference on Computer-Aided Design, Santa Clara, CA, Nov. 10-13, 1986.
ISCAS'86 = Proceedings of the International Symposium on Circuits and Systems, San Jose, CA, May 5-7, 1986.
FJCC = Proceedings of the Fall Joint Computer Conference, Dallas, TX, Nov.2-4, 1986.
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ITC'86 = International Test Conference, Washington, D.C., Sept. 8-11, 1986.
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1986 SCHOLARS VISITING CRC

Dr. Peter Gartner, Budapest Polytechnic University, Budapest, Hungary.

Prof. Ren David, Laboratoire d'Automatique de Grenoble, University of Grenoble, France.

Prof. Ramaswami Dandapani, Youngstown State University, Ohio.

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